

Study of Structural Impact on Annealed CdS Thin Films by Spray Pyrolysis Method

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ABSTRACT

A thin film of CdS is used for in the fabrication of hetero-junction solar cell. The CdS thin film deposited by spray pyrolysis technique shows the direct band gap 2.4 eV on glass substrate of different thicknesses. CdS thin films were annealed in air from 1000C about 3 hours.. The XRD revealed that the films were polycrystalline in nature and with hexagonal phase. The crystallinity of the films was improved by annealing in air at 1000 C.

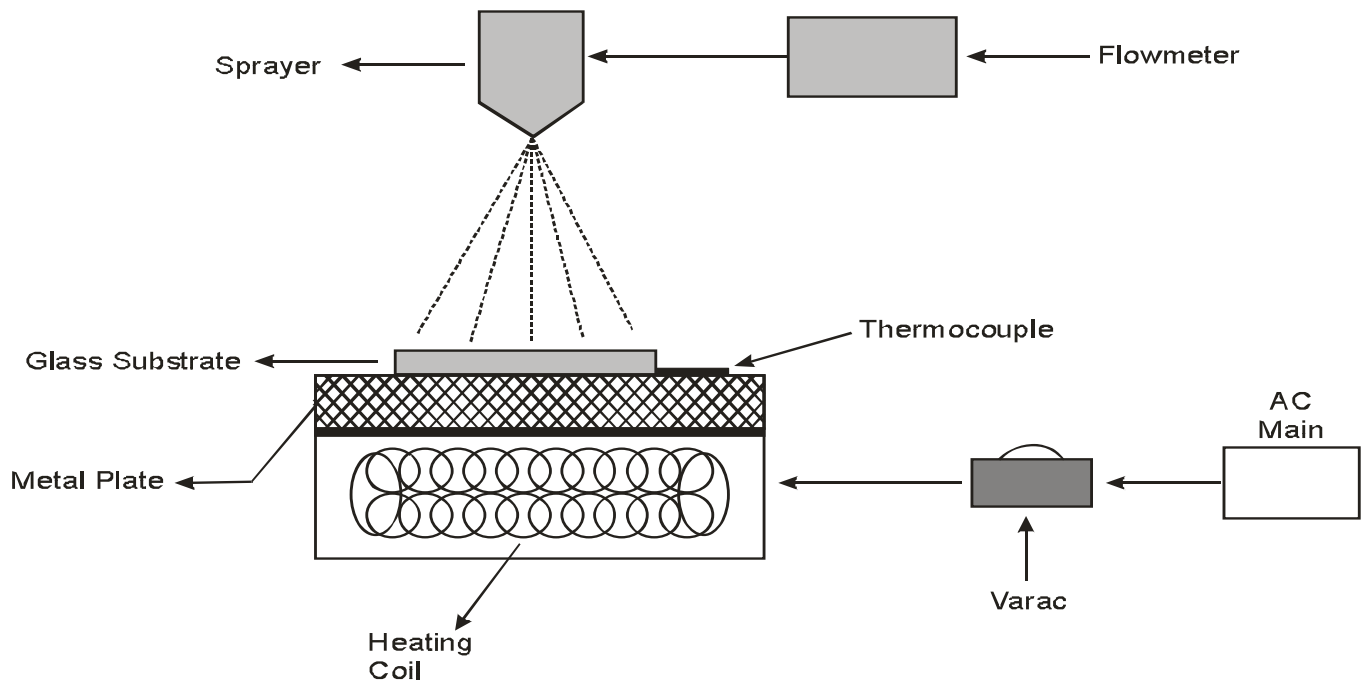
Key Words: Annealed CdS, Spray pyrolysis, XRD, thin film,

I. INTRODUCTION

At present CdS thin films are widely used as the window material in several CdS based thin films solar cells. It belongs to II-VI compound semiconductor materials. Thin films of CdS by spray pyrolysis. This method is simple, inexpensive and suitable for water soluble salts and films are so produced have good adherence to moderately heated substrates. The spray pyrolysis [1] is one of the most popular techniques. CdS [2] and [3]. The chemically prepared CdS films are more ideal window material for solar cells. The optical energy band gap is 2.24 to 2.40 eV [4]. But the films prepared by using spray pyrolysis are quite few in number. In the present work, structural properties of CdS thin films annealed and unannealed of various thicknesses are studied.

II. EXPERIMENTAL DETAILS

A certain amount of pure cadmium chloride (CdCl₂) and thiourea of equimolar concentration (0.01M) was used. CdS films have been produced by spraying the aqueous solution of CdCl₂ and (NH₂)₂CS in a 1:1 (by volume) onto the microscope preheated glass substrates. The solution was thoroughly sprayed by a specially designed glass sprayer on an amorphous preheated cleaned glass substrate at 350°C. The thickness of the films was determined by the weighing method. The annealing of the sample was carried out in air for about 3 hours at 1000°C. The absorption and transmission spectra of annealed and unannealed samples were recorded using Elico SL 159 UV-VIS spectrophotometer. The XRD patterns of annealed and unannealed CdS thin films were recorded with a Phillips X-ray diffractometer.



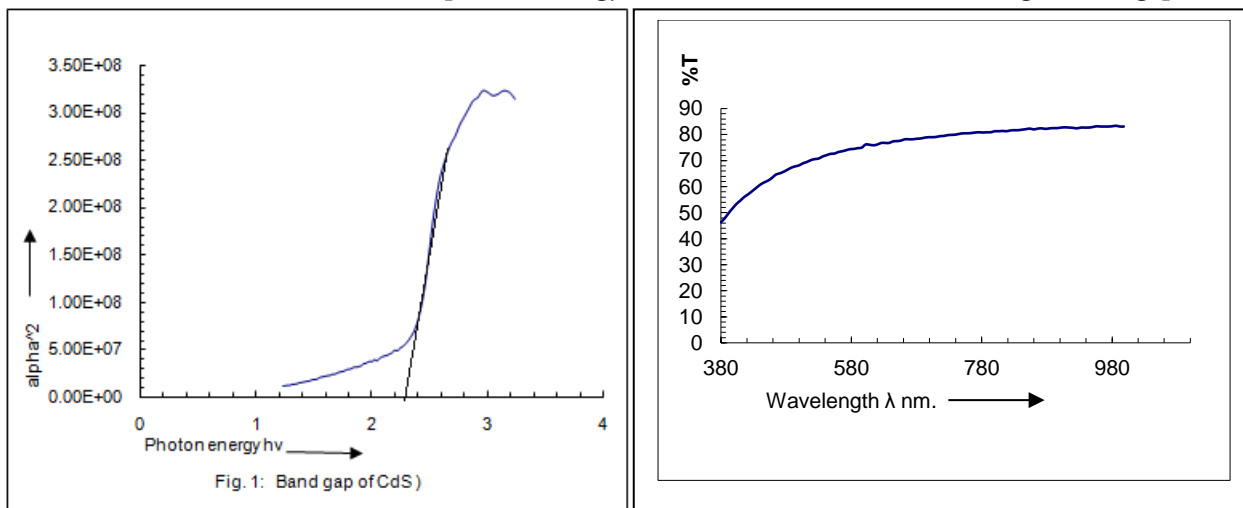
III. RESULT & DISCUSSION

The CdS films were deposited using the pyrolysis method containing various thicknesses. The film deposited by equimolar concentration of cadmium chloride and thiourea was found to have uniformity and adhesion characteristics, and the film thickness depends on the amount of solutions sprayed. The semiconductor band gap E_g was determined by analyzing the optical data.

Energy band gap (E_g) of materials is related to absorption coefficient α as

$$\alpha = \frac{A}{h\nu} (h\nu - E_g)^{1/2} \dots\dots\dots(1)$$

where A is constant, ν is incident photon energy, h is Planck's constant and E_g is band gap.



A plot of $(\alpha h\nu)^2$ versus $(h\nu)$ is shown in Fig. (1) for different thicknesses, giving a fairly good straight line. The band gap E_g was determined to be 2.4 eV [5].

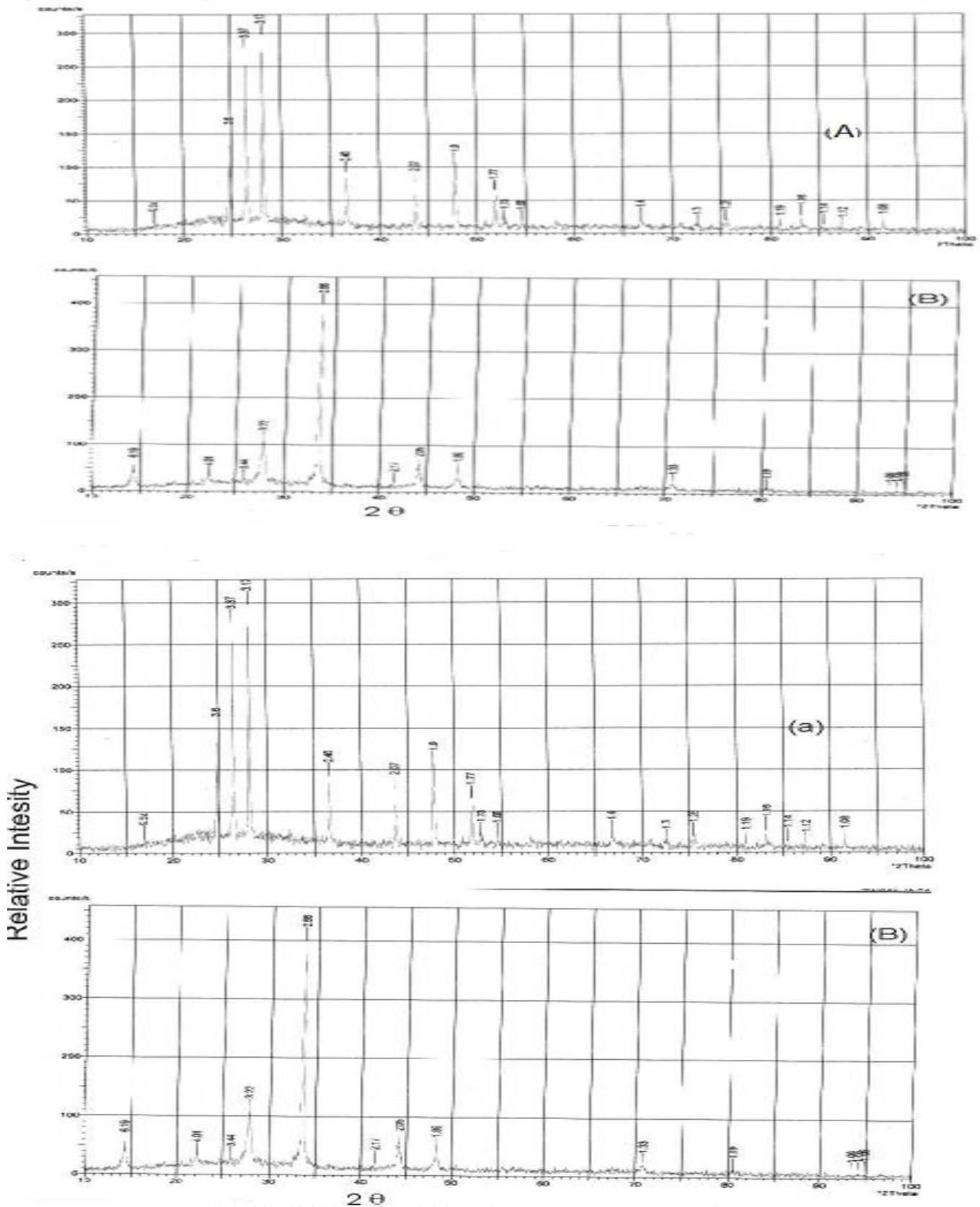


Fig. 2: XRD of CdS a) unannealed and b) annealed

Fig. (2) shows XRD, XRD was used to confirm the crystal structure of CdS thin film annealed for about 3 hours in air. The crystallinity increases with annealing [6].

IV. CONCLUSION

The structural properties of films were studied as a function of substrate temperature, molarity of solution. The range of band gap is 2.35 – 2.4 eV. The CdS thin film prepared by pyrolysis have good adherence and thickness uniformity after annealed. The film is polycrystalline in nature The crystallinity incases with annealing of CdS thin film. Hence these films are best suited for solar cell applications.

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